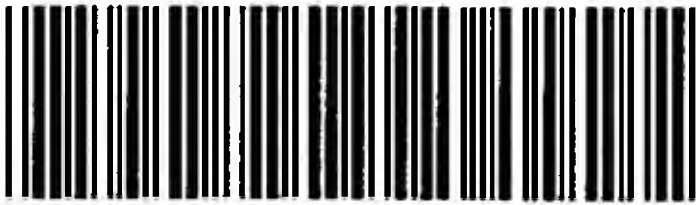
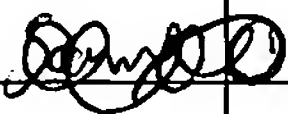


<div>Search Notes</div> <div></div>	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/708,320	LEE, JEN-FENG	
	Examiner	Art Unit	
	Kim R. Lockett	2837	

SEARCHED			
Class	Subclass	Date	Examiner
84	173-179		
	183		
	453		
372	333		
	321		
	328		
292	dis. 28	3/3/05	m

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
			

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR